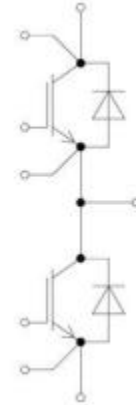


## 1 Features



**IGBT**

**Half bridge IGBT modules**

**$V_{CES} = 1200$**

**$V_{IC\ nom} =$**

**600 A**

Typical Applications

- Switching mode power supply
- AC and DC servo drive amplifier
- UPS Systems

Electrical Features

- Low  $V_{CEsat}$
- Low Switching Losses
- Fast switching and short tail current

Mechanical Features

- 2.5kV Insulation
- High Creepage and Clearance Distances
- High Power Density

<b>Product Name</b>	<b>Package</b>	<b>Version</b>	<b>Date</b>
SPM600V120Y62HS	62mm	V1.0	2025.12.10



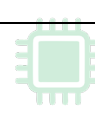
## 2 IGBT (Inverter)

### 2.1 Maximum Rated Values

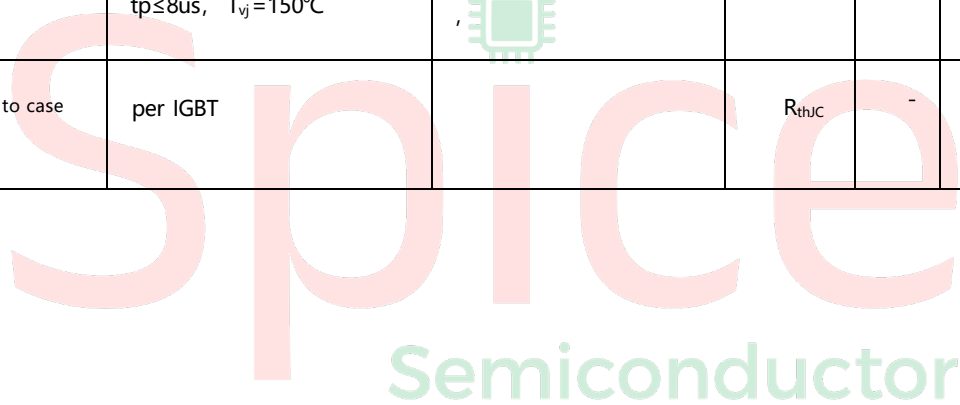
Parameter	Test Conditions	Symbol	Value	Unit
Collector-emitter voltage	$T_{vj} = 25^{\circ}\text{C}$	$V_{CES}$	1200	V
Continuous DC collector current	$T_C = 100^{\circ}\text{C}, T_{vj} = 150^{\circ}\text{C}$	$I_{C\text{ nom}}$	600	A
Repetitive peak collector current	$t_p = 1\text{ms}, T_{vj} = 25^{\circ}\text{C}$	$I_{CRM}$	1200	A
Gate-emitter peak voltage	$T_{vj} = 25^{\circ}\text{C}$	$V_{GES}$	$\pm 20$	V
Total power dissipation	$T_C = 25^{\circ}\text{C}, T_{vj} = 175^{\circ}\text{C}$	$P_{tot}$	1875	W

### 2.2 Characteristic Values

Parameter	Test Conditions		Symbol	Value			Unit
				min	typ	max	
Collector-emitter saturation voltage	$I_C = 600\text{ A}, V_{GE} = 15\text{V},$	$T_{vj} = 25^{\circ}\text{C}$ $T_{vj} = 125^{\circ}\text{C}$ $T_{vj} = 150^{\circ}\text{C}$	$V_{CE\text{ sat}}$	-	1.45 1.60 1.65	1.90 - -	V
Gate threshold voltage	$I_C = 22.8\text{mA}, V_{CE} = V_{GE}, T_{vj} = 25^{\circ}\text{C}$		$V_{GE\text{ th}}$	5.0	5.8	6.5	V
Gate charge	$V_{GE} = -15\text{V} \dots 15\text{V}$		$Q_G$	-	6.9	-	$\mu\text{C}$

Internal gate resistor	$T_{vj} = 25^{\circ}\text{C}$		$R_{Gint}$	-	0.5 3	-	$\Omega$
Input capacitance	$f = 1000\text{K Hz}$ , $V_{CE} = 25\text{V}$ , $V_{GE} = 0\text{V}$ , $T_{vj} = 25^{\circ}\text{C}$		$C_{ies}$	-	86	-	nF
Output capacitance			$C_{oes}$	-	TB D	-	nF
Reverse transfer capacitance			$C_{res}$	-	0. 6	-	nF
Collector-emitter cut-off current	$V_{CE} = 1200\text{V}$ , $V_{GE} = 0\text{V}$ , $T_{vj} = 25^{\circ}\text{C}$		$I_{CES}$	-	-	4	mA
Gate-emitter leakage current	$V_{CE} = 0\text{V}$ , $V_{GE} = 20\text{V}$ , $T_{vj} = 25^{\circ}\text{C}$		$I_{GES}$	-	-	40 0	nA
Turn-on delay time, inductive load	$I_C = 600\text{A}$ , $V_{CE} = 600\text{V}$ , $V_{GE} = -15\text{V}/+15\text{V}$ , $R_{G(on)} = 1.6\ \Omega$ , $R_{G(off)} = 1.6\ \Omega$	 Spice Semiconductor	$t_{d(on)}$	-	19 0 19 0 20 0	-	ns
Rise time, inductive load			$t_r$	-	11 0 11 0 11 0	-	ns
Turn-off delay time, inductive load			$t_{d(off)}$	-	60 0 60 0 62 0	-	ns
Fall time, inductive load			$t_f$	-	15 0 31 0 33 0	-	ns

Turn-on energy loss per pulse			Eon	-	51.9 52.6 57.2	-	mJ
Turn-off energy loss per pulse			Eoff	-	69.3 81.7 88.0	-	mJ
data	$V_{GE} \leq 15V, V_{CC} = 600V, tp \leq 8\mu s, T_{vj} = 150^\circ C$	$V_{CEmax} = V_{CES} - L_{SCE} \cdot di/dt$	$I_{SC}$	-	3100	-	A
Thermal resistance, junction to case	per IGBT		$R_{thJC}$	-	-	0.08	K/W



### 3 Diode (Inverter)

#### 3.1 Maximum Rated Values

Parameter	Test Conditions	Symbol	Value	Unit
Repetitive peak reverse voltage	$T_{vj} = 25^{\circ}\text{C}$	$V_{RRM}$	1200	V
Continuous DC forward current		$I_F$	600	A
Repetitive peak forward current	$t_p = 1\text{ms}, T_{vj} = 25^{\circ}\text{C}$	$I_{FRM}$	1200	A
$I^2t$ -Value	$t_p = 10\text{ms}, T_{vj} = 125^{\circ}\text{C}$	$I^2t$	TBD	$\text{A}^2\text{s}$

#### 3.2 Characteristic Values

Parameter	Test Conditions	Symbol	Value			Unit
			Min	Typ	Max	
Forward voltage	$I_F = 600\text{A}, V_{GE} = 0\text{V},$ $T_{vj} = 25^{\circ}\text{C}$ $T_{vj} = 125^{\circ}\text{C}$ $T_{vj} = 150^{\circ}\text{C}$	$V_F$	-	2.00 1.65 1.60	2.40 -	V
Peak reverse recovery current	$I_F = 600\text{A},$ $V_R = 600\text{V},$	$I_{RM}$	-	290 480 520	-	A
Recovered charge	$V_{GE} = -15\text{V},$ $T_{vj} = 150^{\circ}\text{C}$	$Q_r$	-	38.4 96.5 118.	-	$\mu\text{C}$

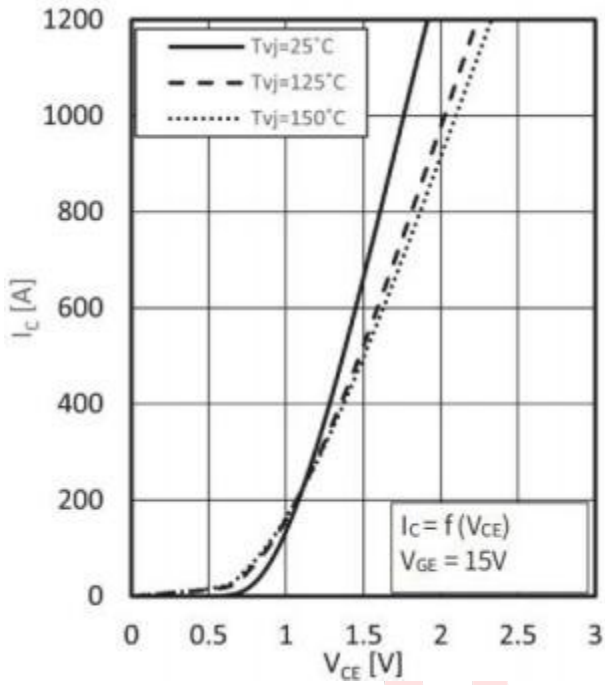
					0		
Reverse recovery energy			$E_{rec}$	-	10.7 27.0 32.8	-	mJ
Thermal resistance, junction to case	per diode		$R_{thJC}$	-	-	0.1 0	K/W



### 4 Module

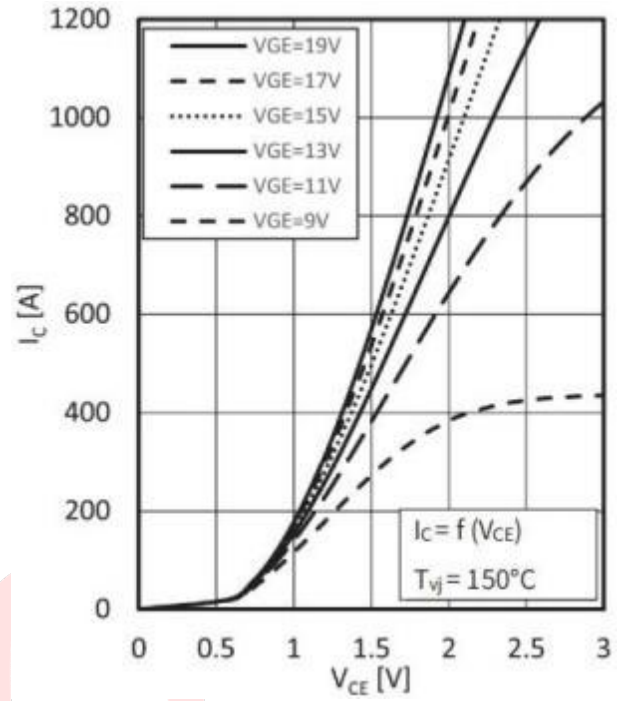
Parameter	Test Conditions	Symbol	Value			Unit
			min	typ	max	
Isolation test voltage	RMS, f = 50 Hz, t = 1 min	$V_{ISOL}$	2500			V
Material of module baseplate			Cu/Ni			
Internal isolation			Al <sub>2</sub> O <sub>3</sub>			
Creepage distance	terminal to terminal	$d_{Creep}$	23			mm
	terminal to heatsink		27			
Clearance	terminal to terminal	$d_{Clear}$	11			mm
	terminal to heatsink		21			
Comperative tracking index		CTI	> 200			
Stray inductance module		$L_{sCE}$	-	20	-	nH
Temperature under switching conditions		$T_{vj,op}$	-	-	150	°C
Storage temperature		$T_{stg}$	-	-	125	°C
Mounting torque for modul mounting		M	3	-	6	Nm
Terminal connection torque		M	2.5	-	5	Nm
Weight		G	-	340	-	g

## 5 Characteristics diagrams



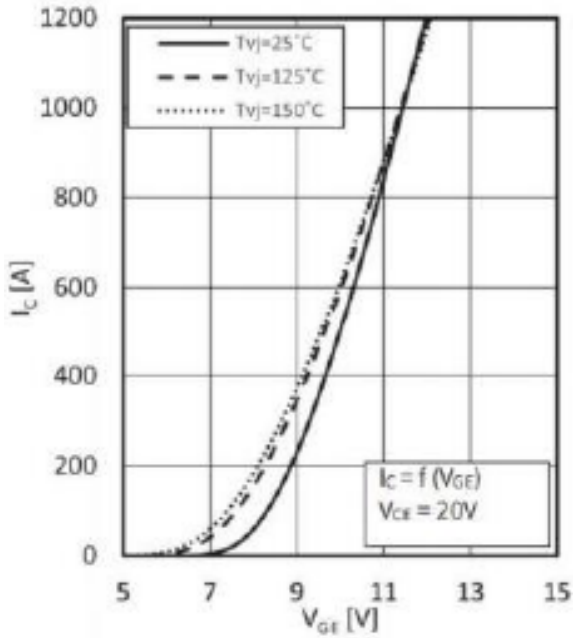
**Figure 1 : Output characteristic (IGBT)**

$I_c = f(V_{CE})$  ,  $V_{GE} = 15V$



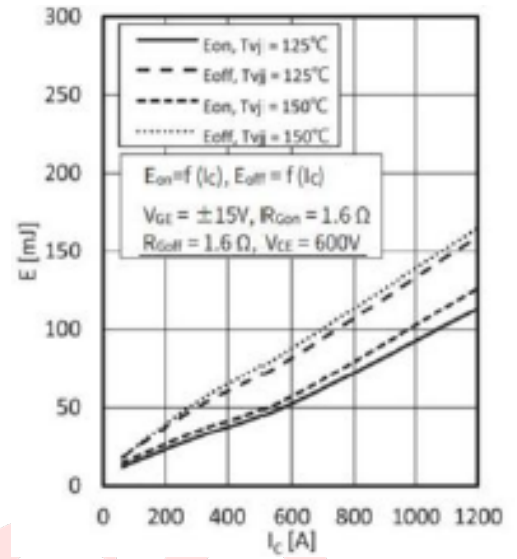
**Figure 2 : Output characteristic (IGBT)**

$I_c = f(V_{CE})$  ,  $T_{vj} = 150^\circ C$

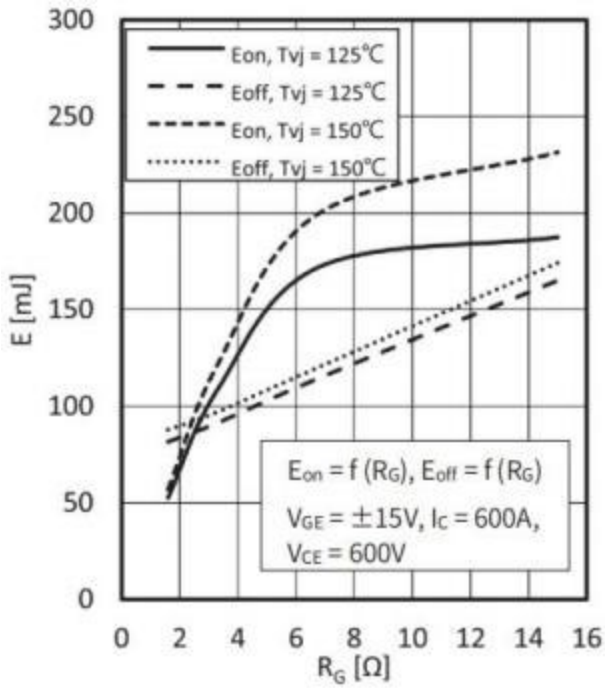


**Figure 3 : Transfer characteristic**

$I_c = f(V_{GE}), V_{CE} = 20\text{V}$

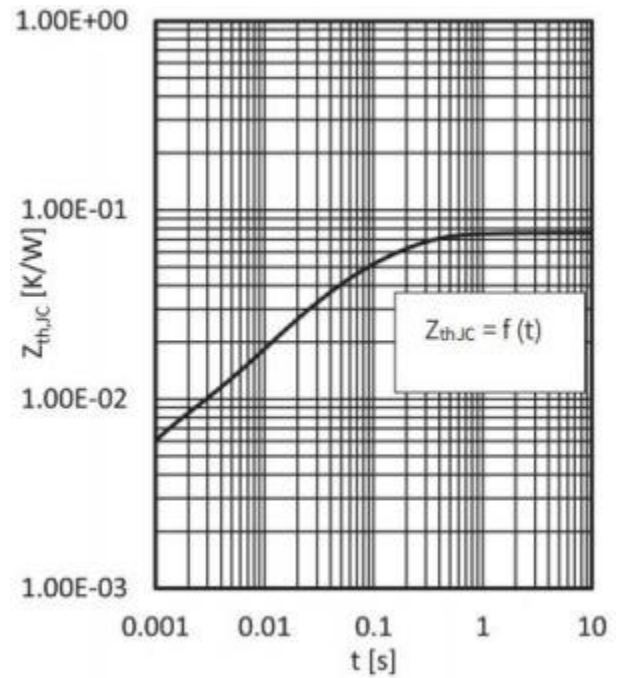


**Figure 4 : Switching losses (IGBT)**



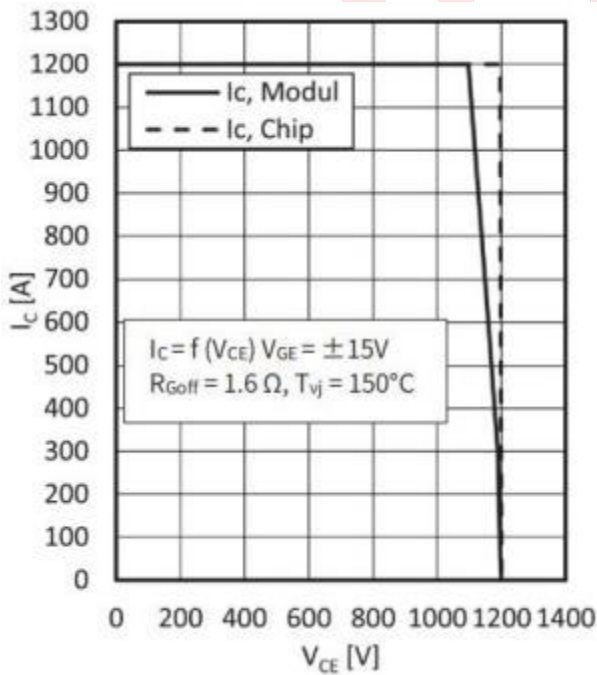
**Figure 5 : Switching losses (IGBT)**

$E_{on} = f(R_G), E_{off} = f(R_G)$



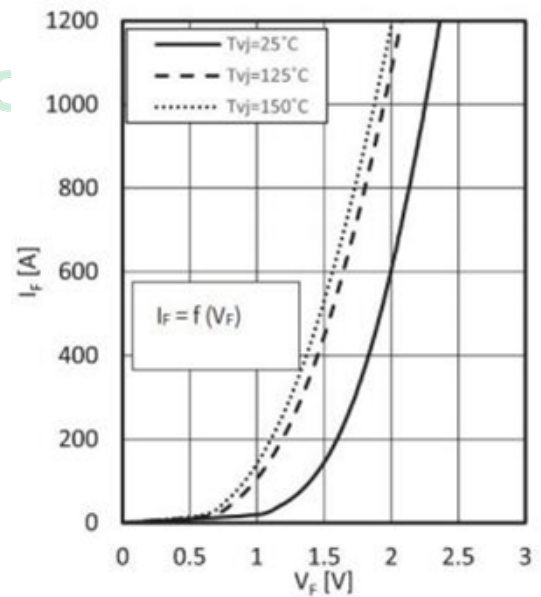
**Figure 6 : Transient thermal impedance IGBT, Inverter**

$Z_{th,jc} = f(t)$

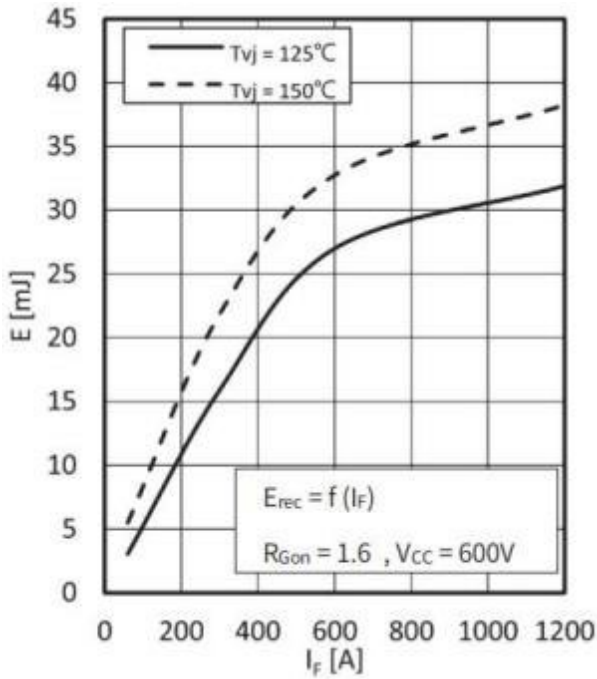


**Figure 7 : RBSOA (IGBT)**

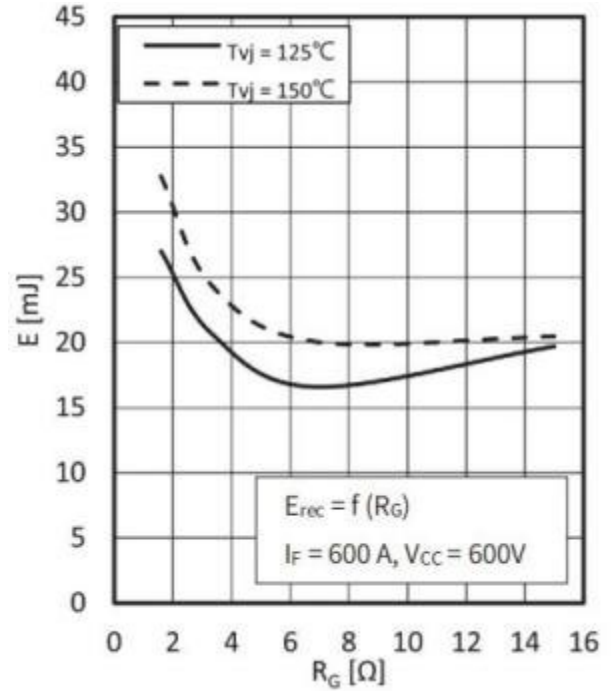
$I_C = f(V_{CE}), V_{GE} = \pm 15$   
 $V, R_{Goff} = 1.6 \Omega, T_{vj} = 150^\circ\text{C}$



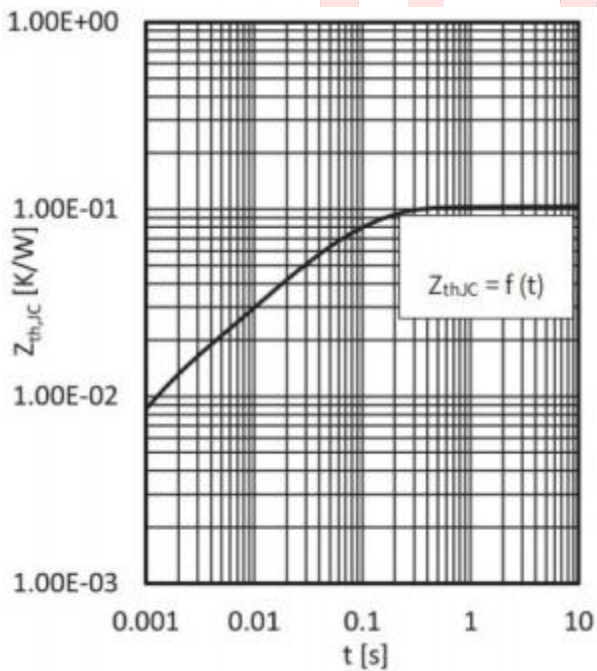
**Figure 8 : Forward characteristic (Diode)**



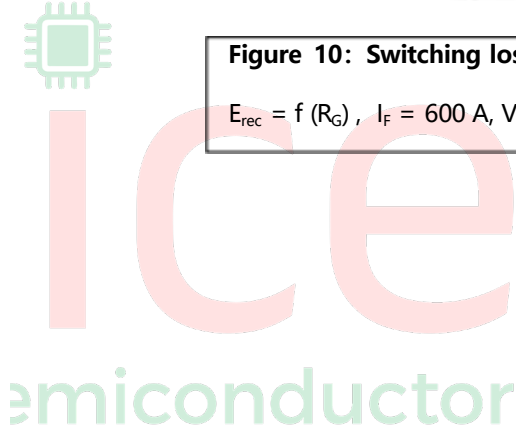
**Figure 9: Switching losses (Diode)**  
 $E_{rec} = f(I_F)$   $R_{Gon} = 1.6 \Omega$   $V_{CE} = 600V$



**Figure 10: Switching losses (Diode)**  
 $E_{rec} = f(R_G)$ ,  $I_F = 600 A$ ,  $V_{CE} = 600 V$



**Figure 11: Transient thermal impedance Diode, Inverter**  
 $Z_{thJC} = f(t)$





## 8 Notice

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